JEDEC STANDARD

Electrically Erasable Programmable ROM (EEPROM) Program / Erase Endurance and Data Retention Stress Test

JESD22-A117E
(Revision of JESD22-A117D, August 2018)

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JEDEC Solid State Technology Association

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ELECTRICALLY ERASABLE PROGRAMMABLE ROM (EEPROM) PROGRAM / ERASE ENDURANCE AND DATA RETENTION STRESS TEST

CONTENTS

		Page
Foreword		**ii**
1	**Scope**	**1**
2	**Terms and definitions**	**1**
3	**Apparatus**	**4**
4	**Procedure**	**4**
	4.1 Program/erase endurance	6
	4.1.1 Test setup	6
	4.1.2 Data cycling	6
	4.2 Data retention	10
	4.2.1 Data programming	10
	4.2.2 Electrical testing and pattern verification	10
	4.2.3 Data retention stress	10
	4.2.4 Electrical testing and pattern verification	11
	4.3 Precautions	11
	4.4 Measurements	11
	4.4.1 Electrical measurements	11
	4.4.2 Required measurements	11
	4.4.3 Measurement conditions	11
5	**Failure criteria**	**12**
	5.1 Handling of transient failures	12
	5.2 Separation of failures into data errors and device failures	12
	5.3 Calculation of UBER	13
	5.3.1 Calculation of UBER in the ideal case	13
	5.3.2 Calculation of UBER in other cases	14
6	**Summary**	**14**
Annex A (informative) Differences between JESD22-A117D and its predecessors		**15**
A.1	(informative) Differences between JESD22-A117D and JESD22-A117C	15
A.2	(informative) Differences between JESD22-A117C and JESD22-A117B	15
A.3	(informative) Differences between JESD22-A117B and JESD22-A117A	16
A.4	(informative) Differences between JESD22-A117A and JESD22-A117	17